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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/697,906	CHIN ET AL.	
Examiner	Art Unit	
Eric D. Bertram	3762	

	SEAR	CHED	
Class	Subclass	Date	Examiner
607	17	9/27/2005	EDB
	18	9/27/2005	EDB
	119	9/27/2005	EDB
	127	9/28/2005	EDB
	129	9/28/2005	EDB
	130	9/28/2005	EDB
600	104-106	9/26/2006	EDB
	123, 129	9/26/2006	EDB
	154-158	9/26/2006	. EDB
		-	

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST notes, see attached	9/29/05	EDB	
Inventor search on eDAN and PALM	9/26/2005	EDB	
Consulted with Carl Layno (3762)	10/3/2005	EDB	
Consulted with Mark Bockelman	7/25/2006	EDB	